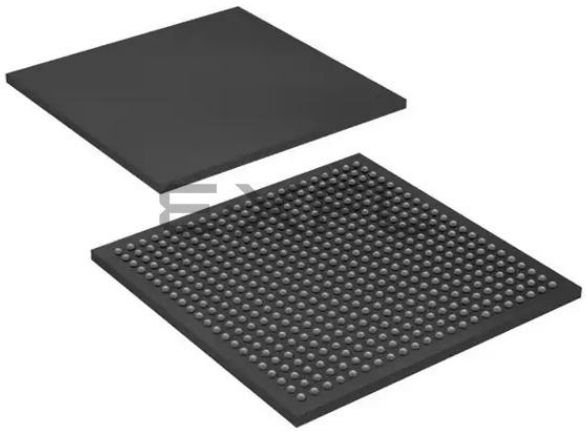


Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	780
Number of Logic Elements/Cells	15600
Total RAM Bits	419328
Number of I/O	342
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s15f484c5

Chapter 3. Configuration & Testing

Chapter 4. Hot Socketing & Power-On Reset

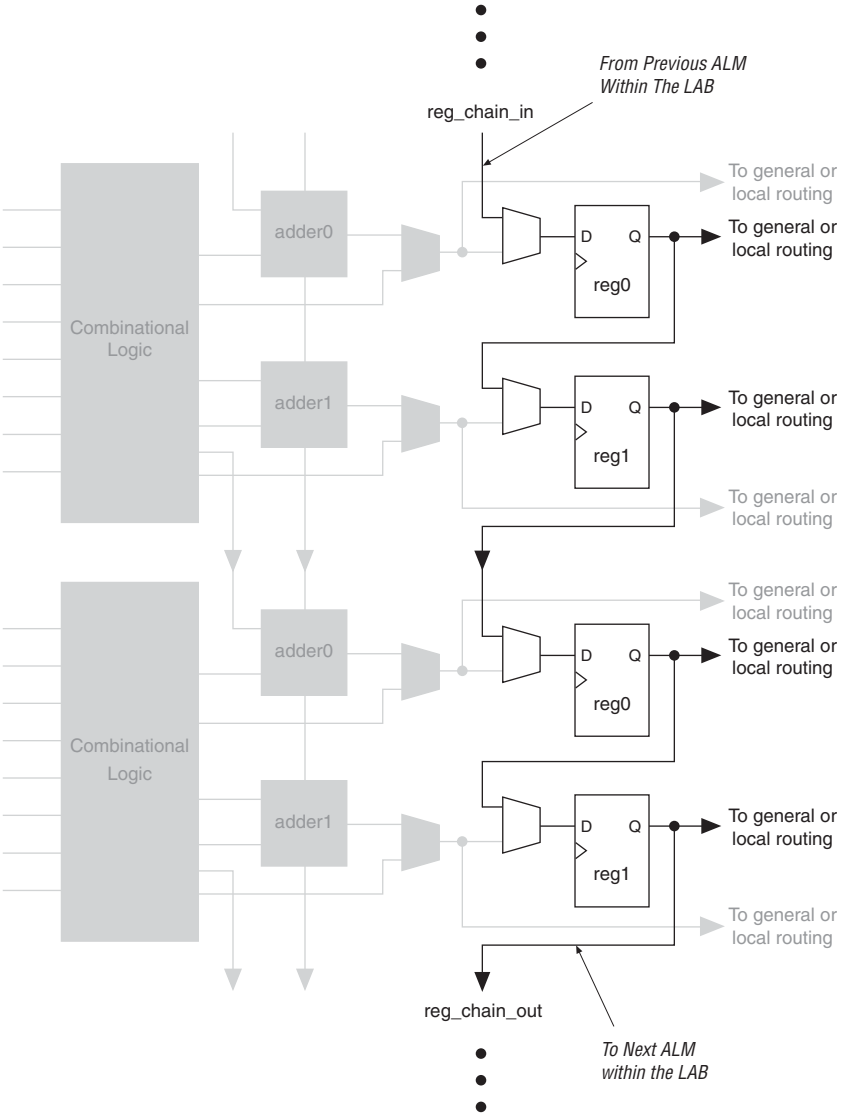
Chapter 5. DC & Switching Characteristics

Stratix II devices are available in up to three speed grades, -3, -4, and -5, with -3 being the fastest. Table 1–5 shows Stratix II device speed-grade offerings.

Table 1–5. Stratix II Device Speed Grades

Device	Temperature Grade	484-Pin FineLine BGA	484-Pin Hybrid FineLine BGA	672-Pin FineLine BGA	780-Pin FineLine BGA	1,020-Pin FineLine BGA	1,508-Pin FineLine BGA
EP2S15	Commercial	-3, -4, -5		-3, -4, -5			
	Industrial	-4		-4			
EP2S30	Commercial	-3, -4, -5		-3, -4, -5			
	Industrial	-4		-4			
EP2S60	Commercial	-3, -4, -5		-3, -4, -5		-3, -4, -5	
	Industrial	-4		-4		-4	
EP2S90	Commercial		-4, -5		-4, -5	-3, -4, -5	-3, -4, -5
	Industrial					-4	-4
EP2S130	Commercial				-4, -5	-3, -4, -5	-3, -4, -5
	Industrial					-4	-4
EP2S180	Commercial					-3, -4, -5	-3, -4, -5
	Industrial					-4	-4

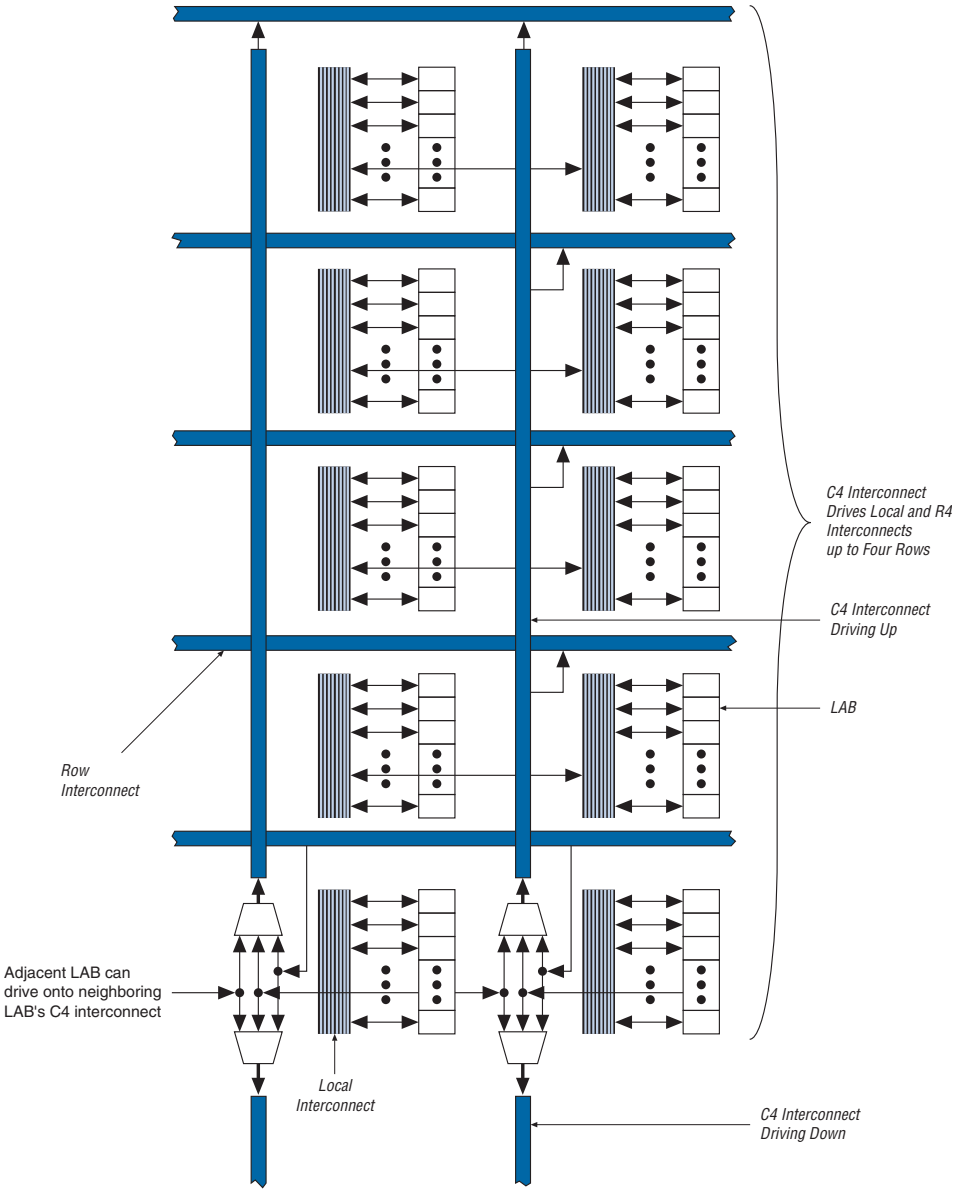
Figure 2–15. Register Chain within an LAB *Note (1)*



Note to Figure 2–15:
(1) The combinational or adder logic can be utilized to implement an unrelated, un-registered function.

See the "MultiTrack Interconnect" on page 2–22 section for more information on register chain interconnect.

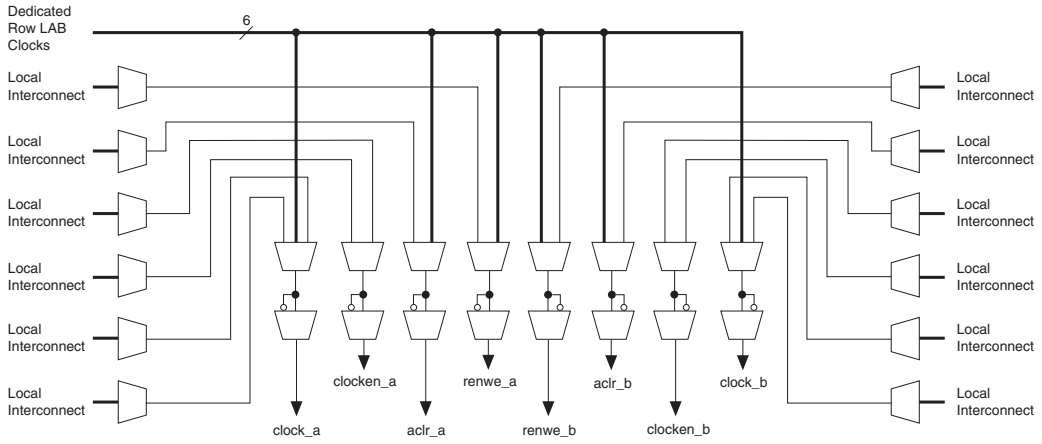
Figure 2–18. C4 Interconnect Connections *Note (1)*



Note to Figure 2–18:
(1) Each C4 interconnect can drive either up or down four rows.

Similar to all RAM blocks, M-RAM blocks can have different clocks on their inputs and outputs. Either of the two clocks feeding the block can clock M-RAM block registers (renwe, address, byte enable, datain, and output registers). The output register can be bypassed. The six `labclk` signals or local interconnect can drive the control signals for the A and B ports of the M-RAM block. ALMs can also control the `clock_a`, `clock_b`, `renwe_a`, `renwe_b`, `clr_a`, `clr_b`, `clocken_a`, and `clocken_b` signals as shown in Figure 2–23.

Figure 2–23. M-RAM Block Control Signals



The R4, R24, C4, and direct link interconnects from adjacent LABs on either the right or left side drive the M-RAM block local interconnect. Up to 16 direct link input connections to the M-RAM block are possible from the left adjacent LABs and another 16 possible from the right adjacent LAB. M-RAM block outputs can also connect to left and right LABs through direct link interconnect. Figure 2–24 shows an example floorplan for the EP2S130 device and the location of the M-RAM interfaces. Figures 2–25 and 2–26 show the interface between the M-RAM block and the logic array.

Digital Signal Processing Block

The most commonly used DSP functions are FIR filters, complex FIR filters, IIR filters, fast Fourier transform (FFT) functions, direct cosine transform (DCT) functions, and correlators. All of these use the multiplier as the fundamental building block. Additionally, some applications need specialized operations such as multiply-add and multiply-accumulate operations. Stratix II devices provide DSP blocks to meet the arithmetic requirements of these functions.

Each Stratix II device has from two to four columns of DSP blocks to efficiently implement DSP functions faster than ALM-based implementations. Stratix II devices have up to 24 DSP blocks per column (see Table 2–5). Each DSP block can be configured to support up to:

- Eight 9 × 9-bit multipliers
- Four 18 × 18-bit multipliers
- One 36 × 36-bit multiplier

As indicated, the Stratix II DSP block can support one 36 × 36-bit multiplier in a single DSP block. This is true for any combination of signed, unsigned, or mixed sign multiplications.

This list only shows functions that can fit into a single DSP block. Multiple DSP blocks can support larger multiplication functions.

PLLs & Clock Networks

Stratix II devices provide a hierarchical clock structure and multiple PLLs with advanced features. The large number of clocking resources in combination with the clock synthesis precision provided by enhanced and fast PLLs provides a complete clock management solution.

Global & Hierarchical Clocking

Stratix II devices provide 16 dedicated global clock networks and 32 regional clock networks (eight per device quadrant). These clocks are organized into a hierarchical clock structure that allows for up to 24 clocks per device region with low skew and delay. This hierarchical clocking scheme provides up to 48 unique clock domains in Stratix II devices.

There are 16 dedicated clock pins (CLK[15..0]) to drive either the global or regional clock networks. Four clock pins drive each side of the device, as shown in Figures 2–31 and 2–32. Internal logic and enhanced and fast PLL outputs can also drive the global and regional clock networks. Each global and regional clock has a clock control block, which controls the selection of the clock source and dynamically enables/disables the clock to reduce power consumption. Table 2–8 shows global and regional clock features.

Table 2–8. Global & Regional Clock Features

Feature	Global Clocks	Regional Clocks
Number per device	16	32
Number available per quadrant	16	8
Sources	CLK pins, PLL outputs, or internal logic	CLK pins, PLL outputs, or internal logic
Dynamic clock source selection	✓ (1)	
Dynamic enable/disable	✓	✓

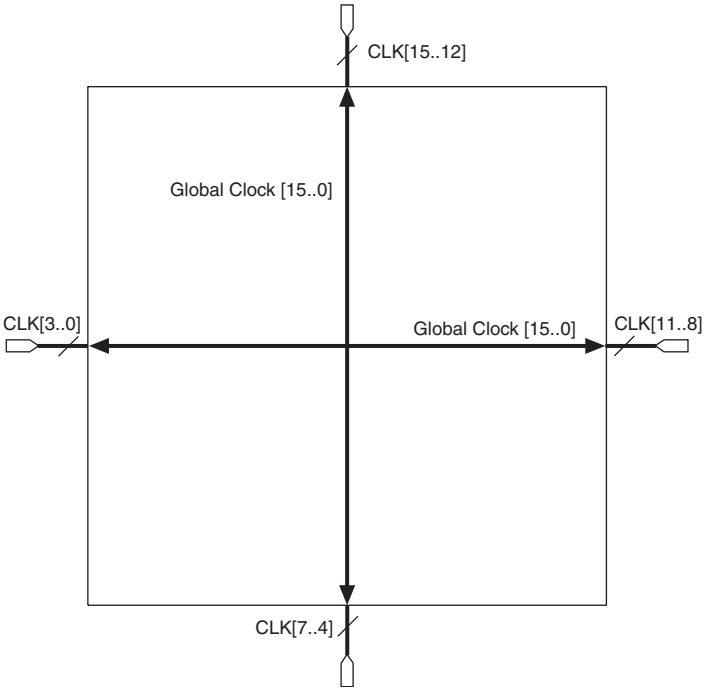
Note to Table 2–8:
(1) Dynamic source clock selection is supported for selecting between CLKp pins and PLL outputs only.

Global Clock Network

These clocks drive throughout the entire device, feeding all device quadrants. The global clock networks can be used as clock sources for all resources in the device-IOEs, ALMs, DSP blocks, and all memory blocks. These resources can also be used for control signals, such as clock enables and synchronous or asynchronous clears fed from the external pin. The

global clock networks can also be driven by internal logic for internally generated global clocks and asynchronous clears, clock enables, or other control signals with large fanout. Figure 2–31 shows the 16 dedicated CLK pins driving global clock networks.

Figure 2–31. Global Clocking



Regional Clock Network

There are eight regional clock networks RCLK[7..0] in each quadrant of the Stratix II device that are driven by the dedicated CLK[15..0] input pins, by PLL outputs, or by internal logic. The regional clock networks provide the lowest clock delay and skew for logic contained in a single quadrant. The CLK clock pins symmetrically drive the RCLK networks in a particular quadrant, as shown in Figure 2–32.

The Quartus II software enables the PLLs and their features without requiring any external devices. Table 2–9 shows the PLLs available for each Stratix II device and their type.

Table 2–9. Stratix II Device PLL Availability

Device	Fast PLLs								Enhanced PLLs			
	1	2	3	4	7	8	9	10	5	6	11	12
EP2S15	✓	✓	✓	✓					✓	✓		
EP2S30	✓	✓	✓	✓					✓	✓		
EP2S60 *(1)*	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓
EP2S90 *(2)*	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓
EP2S130 *(3)*	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓
EP2S180	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓

Notes to Table 2–9:

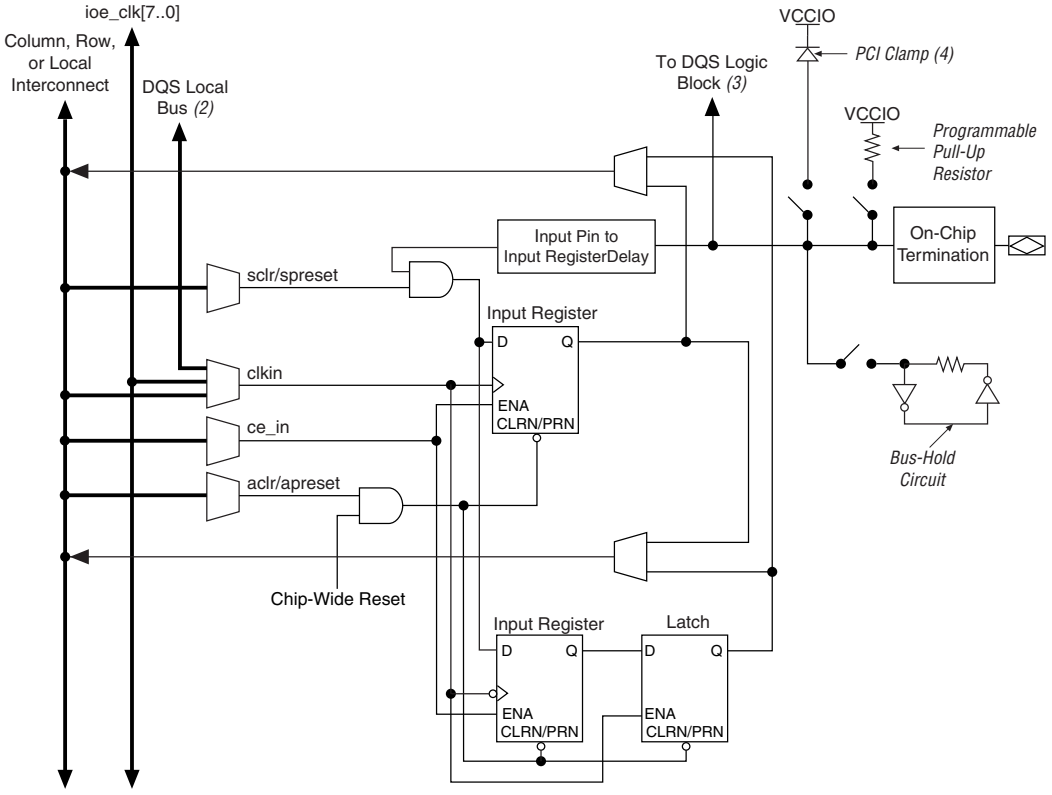
(1) EP2S60 devices in the 1020-pin package contain 12 PLLs. EP2S60 devices in the 484-pin and 672-pin packages contain fast PLLs 1–4 and enhanced PLLs 5 and 6.

(2) EP2S90 devices in the 1020-pin and 1508-pin packages contain 12 PLLs. EP2S90 devices in the 484-pin and 780-pin packages contain fast PLLS 1–4 and enhanced PLLs 5 and 6.

(3) EP2S130 devices in the 1020-pin and 1508-pin packages contain 12PLLs. The EP2S130 device in the 780-pin package contains fast PLLs 1–4 and enhanced PLLs 5 and 6.

When using the IOE for DDR inputs, the two input registers clock double rate input data on alternating edges. An input latch is also used in the IOE for DDR input acquisition. The latch holds the data that is present during the clock high times. This allows both bits of data to be synchronous with the same clock edge (either rising or falling). Figure 2–52 shows an IOE configured for DDR input. Figure 2–53 shows the DDR input timing diagram.

Figure 2–52. Stratix II IOE in DDR Input I/O Configuration *Notes (1), (2), (3)*



Notes to Figure 2–52:

(1) All input signals to the IOE can be inverted at the IOE.
(2) This signal connection is only allowed on dedicated DQ function pins.
(3) This signal is for dedicated DQS function pins only.
(4) The optional PCI clamp is only available on column I/O pins.

- 1.5-V HSTL Class I and II
- 1.8-V HSTL Class I and II
- 1.2-V HSTL
- SSTL-2 Class I and II
- SSTL-18 Class I and II

Table 2–16 describes the I/O standards supported by Stratix II devices.

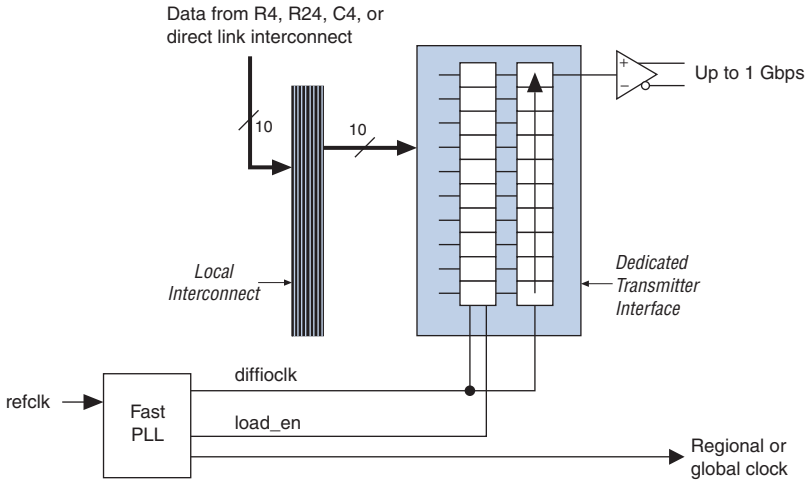
Table 2–16. Stratix II Supported I/O Standards (Part 1 of 2)

I/O Standard	Type	Input Reference Voltage (V_{REF}) (V)	Output Supply Voltage (V_{CCIO}) (V)	Board Termination Voltage (V_{TT}) (V)
LVTTL	Single-ended	-	3.3	-
LVCMOS	Single-ended	-	3.3	-
2.5 V	Single-ended	-	2.5	-
1.8 V	Single-ended	-	1.8	-
1.5-V LVCMOS	Single-ended	-	1.5	-
3.3-V PCI	Single-ended	-	3.3	-
3.3-V PCI-X mode 1	Single-ended	-	3.3	-
LVDS	Differential	-	2.5 *(3)*	-
LVPECL *(1)*	Differential	-	3.3	-
HyperTransport technology	Differential	-	2.5	-
Differential 1.5-V HSTL Class I and II *(2)*	Differential	0.75	1.5	0.75
Differential 1.8-V HSTL Class I and II *(2)*	Differential	0.90	1.8	0.90
Differential SSTL-18 Class I and II *(2)*	Differential	0.90	1.8	0.90
Differential SSTL-2 Class I and II *(2)*	Differential	1.25	2.5	1.25
1.2-V HSTL*(4)*	Voltage-referenced	0.6	1.2	0.6
1.5-V HSTL Class I and II	Voltage-referenced	0.75	1.5	0.75
1.8-V HSTL Class I and II	Voltage-referenced	0.9	1.8	0.9
SSTL-18 Class I and II	Voltage-referenced	0.90	1.8	0.90

Dedicated Circuitry with DPA Support

Stratix II devices support source-synchronous interfacing with LVDS or HyperTransport signaling at up to 1 Gbps. Stratix II devices can transmit or receive serial channels along with a low-speed or high-speed clock. The receiving device PLL multiplies the clock by an integer factor W = 1 through 32. For example, a HyperTransport technology application where the data rate is 1,000 Mbps and the clock rate is 500 MHz would require that W be set to 2. The SERDES factor *J* determines the parallel data width to deserialize from receivers or to serialize for transmitters. The SERDES factor *J* can be set to 4, 5, 6, 7, 8, 9, or 10 and does not have to equal the PLL clock-multiplication W value. A design using the dynamic phase aligner also supports all of these *J* factor values. For a *J* factor of 1, the Stratix II device bypasses the SERDES block. For a *J* factor of 2, the Stratix II device bypasses the SERDES block, and the DDR input and output registers are used in the IOE. Figure 2–58 shows the block diagram of the Stratix II transmitter channel.

Figure 2–58. Stratix II Transmitter Channel



Each Stratix II receiver channel features a DPA block for phase detection and selection, a SERDES, a synchronizer, and a data realigner circuit. You can bypass the dynamic phase aligner without affecting the basic source-synchronous operation of the channel. In addition, you can dynamically switch between using the DPA block or bypassing the block via a control signal from the logic array. Figure 2–59 shows the block diagram of the Stratix II receiver channel.

error status information. This dedicated remote system upgrade circuitry avoids system downtime and is the critical component for successful remote system upgrades.

RSC is supported in the following Stratix II configuration schemes: FPP, AS, PS, and PPA. RSC can also be implemented in conjunction with advanced Stratix II features such as real-time decompression of configuration data and design security using AES for secure and efficient field upgrades.

See the *Remote System Upgrades With Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook* for more information about remote configuration in Stratix II devices.

Configuring Stratix II FPGAs with JRunner

JRunner is a software driver that configures Altera FPGAs, including Stratix II FPGAs, through the ByteBlaster II or ByteBlasterMV cables in JTAG mode. The programming input file supported is in Raw Binary File **(.rbf)** format. JRunner also requires a Chain Description File **(.cdf)** generated by the Quartus II software. JRunner is targeted for embedded JTAG configuration. The source code is developed for the Windows NT operating system (OS), but can be customized to run on other platforms.

For more information on the JRunner software driver, see the *JRunner Software Driver: An Embedded Solution to the JTAG Configuration White Paper* and the source files on the Altera web site **(www.altera.com)**.

Programming Serial Configuration Devices with SRunner

A serial configuration device can be programmed in-system by an external microprocessor using SRunner. SRunner is a software driver developed for embedded serial configuration device programming that can be easily customized to fit in different embedded systems. SRunner is able to read a **.rpd** file (Raw Programming Data) and write to the serial configuration devices. The serial configuration device programming time using SRunner is comparable to the programming time when using the Quartus II software.

For more information about SRunner, see the *SRunner: An Embedded Solution for EPCS Programming* White Paper and the source code on the Altera web site at **www.altera.com**.

For more information on programming serial configuration devices, see the Serial Configuration Devices (EPCS1 & EPCS4) Data Sheet in the *Configuration Handbook*.

Figure 3–1. External Temperature-Sensing Diode

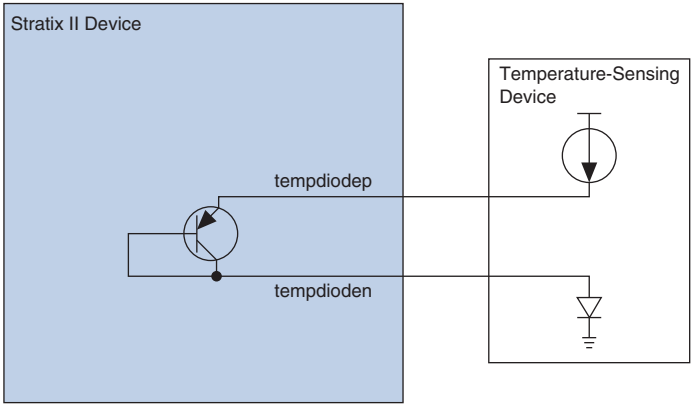


Table 3–6 shows the specifications for bias voltage and current of the Stratix II temperature sensing diode.

Table 3–6. Temperature-Sensing Diode Electrical Characteristics

Parameter	Minimum	Typical	Maximum	Unit
IBIAS high	80	100	120	µA
IBIAS low	8	10	12	µA
VBP - VBN	0.3		0.9	V
VBN		0.7		V
Series resistance			3	Ω

Table 3–7. Document Revision History (Part 2 of 2)

Date and Document Version	Changes Made	Summary of Changes
April 2006, v4.1	Updated "Device Security Using Configuration Bitstream Encryption" section.	—
December 2005, v4.0	Updated "Software Interface" section.	—
May 2005, v3.0	• Updated "IEEE Std. 1149.1 JTAG Boundary-Scan Support" section. • Updated "Operating Modes" section.	—
January 2005, v2.1	Updated JTAG chain device limits.	—
January 2005, v2.0	Updated Table 3–3.	—
July 2004, v1.1	• Added "Automated Single Event Upset (SEU) Detection" section. • Updated "Device Security Using Configuration Bitstream Encryption" section. • Updated Figure 3–2.	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—

I/O Delays

See Tables 5–72 through 5–76 for I/O delays.

Table 5–72. I/O Delay Parameters

Symbol	Parameter
t_{DIP}	Delay from I/O datain to output pad
t_{OP}	Delay from I/O output register to output pad
t_{PCOUT}	Delay from input pad to I/O dataout to core
t_{PI}	Delay from input pad to I/O input register

Table 5–73. Stratix II I/O Input Delay for Column Pins (Part 1 of 3)

I/O Standard	Parameter	Minimum Timing		-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
		Industrial	Commercial					
LVTTL	t_{PI}	674	707	1223	1282	1405	1637	ps
	t_{PCOUT}	408	428	787	825	904	1054	ps
2.5 V	t_{PI}	684	717	1210	1269	1390	1619	ps
	t_{PCOUT}	418	438	774	812	889	1036	ps
1.8 V	t_{PI}	747	783	1366	1433	1570	1829	ps
	t_{PCOUT}	481	504	930	976	1069	1246	ps
1.5 V	t_{PI}	749	786	1436	1506	1650	1922	ps
	t_{PCOUT}	483	507	1000	1049	1149	1339	ps
LVCMOS	t_{PI}	674	707	1223	1282	1405	1637	ps
	t_{PCOUT}	408	428	787	825	904	1054	ps
SSTL-2 Class I	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
SSTL-2 Class II	t_{PI}	507	530	818	857	939	1094	ps
	t_{PCOUT}	241	251	382	400	438	511	ps
SSTL-18 Class I	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
SSTL-18 Class II	t_{PI}	543	569	898	941	1031	1201	ps
	t_{PCOUT}	277	290	462	484	530	618	ps
1.5-V HSTL Class I	t_{PI}	560	587	993	1041	1141	1329	ps
	t_{PCOUT}	294	308	557	584	640	746	ps

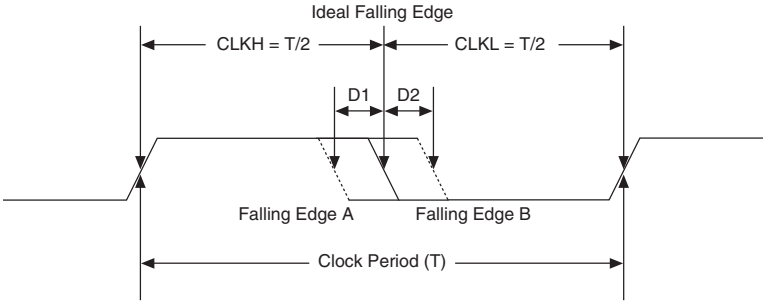
Table 5–75. Stratix II I/O Output Delay for Column Pins (Part 4 of 8)

I/O Standard	Drive Strength	Parameter	Minimum Timing		-3 Speed Grade (3)	-3 Speed Grade (4)	-4 Speed Grade	-5 Speed Grade	Unit
			Industrial	Commercial					
SSTL-18 Class I	4 mA	t_{OP}	909	953	1690	1773	1942	2012	ps
		t_{DIP}	929	975	1756	1843	2018	2102	ps
	6 mA	t_{OP}	914	958	1656	1737	1903	1973	ps
		t_{DIP}	934	980	1722	1807	1979	2063	ps
	8 mA	t_{OP}	894	937	1640	1721	1885	1954	ps
		t_{DIP}	914	959	1706	1791	1961	2044	ps
	10 mA	t_{OP}	898	942	1638	1718	1882	1952	ps
		t_{DIP}	918	964	1704	1788	1958	2042	ps
	12 mA (1)	t_{OP}	891	936	1626	1706	1869	1938	ps
		t_{DIP}	911	958	1692	1776	1945	2028	ps
SSTL-18 Class II	8 mA	t_{OP}	883	925	1597	1675	1835	1904	ps
		t_{DIP}	903	947	1663	1745	1911	1994	ps
	16 mA	t_{OP}	894	937	1578	1655	1813	1882	ps
		t_{DIP}	914	959	1644	1725	1889	1972	ps
	18 mA	t_{OP}	890	933	1585	1663	1821	1890	ps
		t_{DIP}	910	955	1651	1733	1897	1980	ps
	20 mA (1)	t_{OP}	890	933	1583	1661	1819	1888	ps
		t_{DIP}	910	955	1649	1731	1895	1978	ps
1.8-V HSTL Class I	4 mA	t_{OP}	912	956	1608	1687	1848	1943	ps
		t_{DIP}	932	978	1674	1757	1924	2033	ps
	6 mA	t_{OP}	917	962	1595	1673	1833	1928	ps
		t_{DIP}	937	984	1661	1743	1909	2018	ps
	8 mA	t_{OP}	896	940	1586	1664	1823	1917	ps
		t_{DIP}	916	962	1652	1734	1899	2007	ps
	10 mA	t_{OP}	900	944	1591	1669	1828	1923	ps
		t_{DIP}	920	966	1657	1739	1904	2013	ps
	12 mA (1)	t_{OP}	892	936	1585	1663	1821	1916	ps
		t_{DIP}	912	958	1651	1733	1897	2006	ps

Table 5–78. Maximum Output Toggle Rate on Stratix II Devices (Part 1 of 5) *Note (1)*

I/O Standard	Drive Strength	Column I/O Pins (MHz)			Row I/O Pins (MHz)			Clock Outputs (MHz)		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
3.3-V LVTTL	4 mA	270	225	210	270	225	210	270	225	210
	8 mA	435	355	325	435	355	325	435	355	325
	12 mA	580	475	420	580	475	420	580	475	420
	16 mA	720	594	520	-	-	-	720	594	520
	20 mA	875	700	610	-	-	-	875	700	610
	24 mA	1,030	794	670	-	-	-	1,030	794	670
3.3-V LVCMOS	4 mA	290	250	230	290	250	230	290	250	230
	8 mA	565	480	440	565	480	440	565	480	440
	12 mA	790	710	670	-	-	-	790	710	670
	16 mA	1,020	925	875	-	-	-	1,020	925	875
	20 mA	1,066	985	935	-	-	-	1,066	985	935
	24 mA	1,100	1,040	1,000	-	-	-	1,100	1,040	1,000
2.5-V LVTTL/LVCMOS	4 mA	230	194	180	230	194	180	230	194	180
	8 mA	430	380	380	430	380	380	430	380	380
	12 mA	630	575	550	630	575	550	630	575	550
	16 mA	930	845	820	-	-	-	930	845	820
1.8-V LVTTL/LVCMOS	2 mA	120	109	104	120	109	104	120	109	104
	4 mA	285	250	230	285	250	230	285	250	230
	6 mA	450	390	360	450	390	360	450	390	360
	8 mA	660	570	520	660	570	520	660	570	520
	10 mA	905	805	755	-	-	-	905	805	755
	12 mA	1,131	1,040	990	-	-	-	1,131	1,040	990
1.5-V LVTTL/LVCMOS	2 mA	244	200	180	244	200	180	244	200	180
	4 mA	470	370	325	470	370	325	470	370	325
	6 mA	550	430	375	-	-	-	550	430	375
	8 mA	625	495	420	-	-	-	625	495	420
SSTL-2 Class I	8 mA	400	300	300	-	-	-	400	300	300
	12 mA	400	400	350	400	350	350	400	400	350
SSTL-2 Class II	16 mA	350	350	300	350	350	300	350	350	300
	20 mA	400	350	350	-	-	-	400	350	350
	24 mA	400	400	350	-	-	-	400	400	350

Figure 5–7. Duty Cycle Distortion



DCD expressed in absolution derivation, for example, D1 or D2 in Figure 5–7, is clock-period independent. DCD can also be expressed as a percentage, and the percentage number is clock-period dependent. DCD as a percentage is defined as

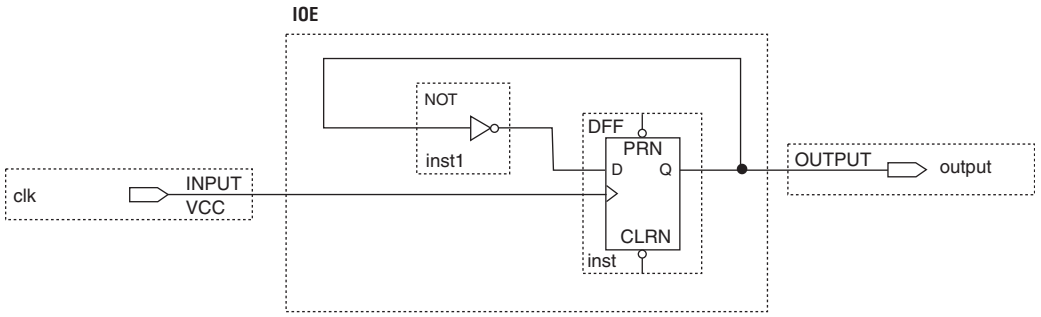
(T/2 – D1) / T (the low percentage boundary)

(T/2 + D2) / T (the high percentage boundary)

DCD Measurement Techniques

DCD is measured at an FPGA output pin driven by registers inside the corresponding I/O element (IOE) block. When the output is a single data rate signal (non-DDIO), only one edge of the register input clock (positive or negative) triggers output transitions (Figure 5–8). Therefore, any DCD present on the input clock signal or caused by the clock input buffer or different input I/O standard does not transfer to the output signal.

Figure 5–8. DCD Measurement Technique for Non-DDIO (Single-Data Rate) Outputs



Therefore, the DCD percentage for the 267 MHz SSTL-2 Class II DDIO row output clock on a –3 device ranges from 48.4% to 51.6%.

Table 5–83. Maximum DCD for DDIO Output on Row I/O Pins Without PLL in the Clock Path for -4 & -5 Devices *Notes (1), (2)*

Row DDIO Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	LVDS/ HyperTransport Technology	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	3.3 V	
3.3-V LVTTL	440	495	170	160	105	ps
3.3-V LVCMOS	390	450	120	110	75	ps
2.5 V	375	430	105	95	90	ps
1.8 V	325	385	90	100	135	ps
1.5-V LVCMOS	430	490	160	155	100	ps
SSTL-2 Class I	355	410	85	75	85	ps
SSTL-2 Class II	350	405	80	70	90	ps
SSTL-18 Class I	335	390	65	65	105	ps
1.8-V HSTL Class I	330	385	60	70	110	ps
1.5-V HSTL Class I	330	390	60	70	105	ps
LVDS/ HyperTransport technology	180	180	180	180	180	ps

Notes to Table 5–83:
(1) Table 5–83 assumes the input clock has zero DCD.
(2) The DCD specification is based on a no logic array noise condition.

Table 5–84. Maximum DCD for DDIO Output on Column I/O Pins Without PLL in the Clock Path for -3 Devices (Part 1 of 2) *Notes (1), (2)*

DDIO Column Output I/O Standard	Maximum DCD Based on I/O Standard of Input Feeding the DDIO Clock Port (No PLL in the Clock Path)					Unit
	TTL/CMOS		SSTL-2	SSTL/HSTL	1.2-V HSTL	
	3.3/2.5 V	1.8/1.5 V	2.5 V	1.8/1.5 V	1.2 V	
3.3-V LVTTL	260	380	145	145	145	ps
3.3-V LVCMOS	210	330	100	100	100	ps
2.5 V	195	315	85	85	85	ps